

**Notice of References Cited**

Application/Control No.

10/539,757

Applicant(s)/Patent Under  
Reexamination  
YOSHIDA ET AL.

Examiner

DEREK S. CHAPEL

Art Unit

2872

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,481,384	01-1996	Kramer et al.	359/17
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
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	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
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**NON-PATENT DOCUMENTS**

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